CM 200



ADVANCED CENTRATION TESTING SYSTEM

_ precise measuring system for measuring centration on precision optical lenses

_ simultanious measurement of the runout of upper and lower surface plus edge runout relative to the rotational position on the rotational position controlled lens.

_ high precise, balanced linear axis, air bearing guided, for each autocollimator

_ accurate, contactless edge detection sensor located on positionable X-Z slide

_ precise, encoded rotational axis - airbearing guided - for lens movement

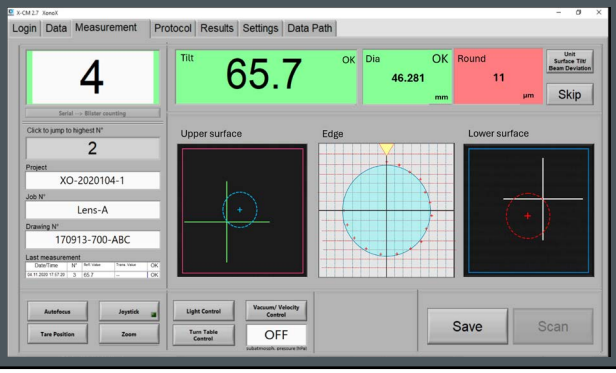
_ diameter and taper analysis optional

_ small foot print and exceptional value combined with high accuracy and and rigit, maitenance free design

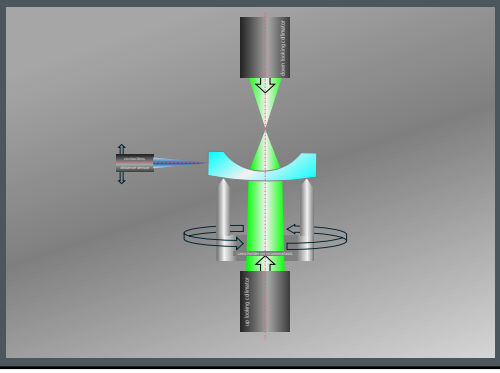
_ innovative, powerful and user friendly analysis system X-cm with different smart and intelligent modes to suit various applications

_ compatibility with XONOX IQC system for automated setup and automated documentation of measurements in series.

X-cm user interface



Measuring Principle



WORKING RANGE	up to lens diameter 200mm				
POSITIONING AXIS	counterbalanced, air bearing guided axis with smooth, „zero weight“ electronic driven equiped with linear encoder - software controlled movement. Wear out and maintenance free design. precision air bearing guided rotational axis equipped with rotary encoder - electronic driven and software controlled. Wear out and maintenance free design.				
MEASURING SYSTEM	- 2x autocollimators (DL and UL) with high resolution CMOS cameras - high precision contactless distance measuring sensor.				
DIMENSIONS (WxDxH)	800 x 900 x 2650 mm when using touch screen and integrated PC for fringe analysis (additional space required if separate PC is used for fringe analysis, XONOX PC-table optionally available)				
WEIGHT	approx. 750kg	**CONNECTIONS**	110-240 V / 50-60 Hz, compressed air: 6 bar	**COLOR**	Light grey RAL 7035

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iQC READY

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METROLOGY FOR OPTICS REDEFINED